

This listing of claims will replace all prior versions,
and listings, of claims in the application:

Claims 1-11 (canceled)

1 Claim 12 (original): A distance-measuring device
2 comprising:
3 an AF area sensor formed on a semiconductor
4 substrate for pick upping two images formed to have
5 a parallax therebetween, and integrating sensor data that
6 corresponds to an appropriate amount of light;
7 a photo reception signal processing circuit formed
8 on the semiconductor substrate for creating outline data
9 based on the sensor data from the AF area sensor;
10 a control section detecting a main subject in
11 a photography screen on the basis of the outline data
12 output from the photo reception signal processing
13 circuit, and setting, in the photography screen, a
14 distance-measuring area including the main subject; and
15 a distance-measuring section for executing distance
16 measurement in the distance-measuring area set by the
17 control section.

1 Claim 13 (original): The distance-measuring device
2 according to claim 12, wherein the AF area sensor
3 includes:

4 a pixel area in which photoelectric elements are
5 arranged in a matrix, the photoelectric elements each
6 receiving image for distance measurement formed by two
7 photoelectric lenses located before the AF area sensor
8 and having a parallax therebetween;
9 a horizontal/vertical control circuit operable under
10 the control of the control section for scanning and
11 outputting an amount of the image for distance
12 measurement accumulated by the photoelectric elements
13 included in the pixel area;
14 an output circuit for amplifying, by a predetermined
15 level, a signal output from the horizontal/vertical
16 control circuit; and
17 a sensor control circuit operable under the control
18 of the control section for controlling received-image
19 accumulation and output operation of the AF area sensor,
20 the pixel area, the horizontal/vertical control
21 circuit, the output circuit and the sensor control
22 circuit being formed on a silicon substrate by a CMOS
23 process.

1 Claim 14 (original): The distance-measuring device
2 according to claim 13, wherein the horizontal/vertical
3 control circuit of the AF area sensor sequentially
4 applies a sensitivity control signal to the photoelectric
5 elements in units of one row of the matrix, thereby
6 extracting an amount of image for distance measurement

7 accumulated by those of photoelectric elements, which are
8 located in each column of the matrix, extracting only a
9 column at which the amount of image for distance
10 measurement changes, detecting, simultaneously and in
11 a parallel manner, pieces of outline data each
12 corresponding to one scanning line, and outputting
13 the detection result as the outline data.

Claims 15-28 (canceled)